

(Note 1c)

(Note 1)

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THERMAL CHARACTERISTICS

T_,T_{STG}

R_{eja}

R_{euc}

Operating and Storage Temperature Range

Thermal Resistance, Junction-to-Case

Thermal Resistance, Junction-to-Ambient (Note 1a)

FDS6690 Rev.C

°С

°C/W

°C/W

1

-55 to 150

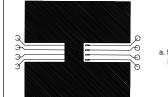
50

25

Symbol	Parameter	Conditions	Min	Тур	Max	Units
OFF CHAR	ACTERISTICS			•	•	•
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 V, I_{D} = 250 \mu A$	30			V
$\Delta BV_{DSS} / \Delta T_{J}$	Breakdown Voltage Temp. Coefficient	$I_{\rm D}$ = 250 μ A, Referenced to 25 °C		21		mV /°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24 V, V_{GS} = 0 V$			1	μA
		$T_{J} = 55^{\circ}C$			10	μA
	Gate - Body Leakage, Forward	$V_{GS} = 20 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$			100	nA
I _{GSSR}	Gate - Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$			-100	nA
ON CHARA	CTERISTICS (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{\rm DS} = V_{\rm GS}, \ I_{\rm D} = 250 \ \mu A$	1	2	3	V
$\Delta V_{GS(th)} / \Delta T_{J}$	Gate Threshold Voltage Temp. Coefficient	$I_{D} = 250 \ \mu\text{A}$, Referenced to $25 \ ^{\circ}\text{C}$		-4.5		mV /°C
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 10 \text{ A}$		0.011	0.0135	Ω
		T _J =125°C		0.018	0.023	
		$V_{GS} = 4.5 \text{ V}, \text{ I}_{D} = 9 \text{ A}$		0.017	0.02	
I _{D(ON)}	On-State Drain Current	$V_{\rm GS} = 10 \text{ V}, V_{\rm DS} = 5 \text{ V}$	50			Α
9 _{FS}	Forward Transconductance	$V_{\rm DS} = 10 \text{ V}, \text{ I}_{\rm D} = 10 \text{ A}$		27		S
DYNAMIC	CHARACTERISTICS			•		•
C _{iss}	Input Capacitance	$V_{DS} = 15 V, V_{GS} = 0 V,$ f = 1.0 MHz		1340		pF
C _{oss}	Output Capacitance	f = 1.0 MHz		340		pF
C _{rss}	Reverse Transfer Capacitance			125		pF
SWITCHING	G CHARACTERISTICS (Note 2)					
t _{D(on)}	Turn - On Delay Time	$V_{DS} = 15 \text{ V}, \text{ I}_{D} = 1 \text{ A}$		12	22	ns
ţ	Turn - On Rise Time	V_{GS} = 10 V , R_{GEN} = 6Ω		13	24	ns
t _{D(off)}	Turn - Off Delay Time			38	60	ns
t,	Turn - Off Fall Time			10	18	ns
Q _g	Total Gate Charge	$V_{\rm DS} = 15 \text{ V}, \ \text{I}_{\rm D} = 10 \text{ A},$		13	18	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = 5 V$		5		nC
Q _{gd}	Gate-Drain Charge			4		nC
DRAIN-SOL	IRCE DIODE CHARACTERISTICS AND MAX	IMUM RATINGS				
l _s	Maximum Continuous Drain-Source Diode Forward Current				2.1	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 V, I_{S} = 2.1 A$ (Note 2)		0.73	1.2	V

Notes:

1. R_{BM} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{BM} is guaranteed by design while R_{BA} is determined by the user's board design.



a. 50°C/W on a 0.5 in² pad of 2oz copper.

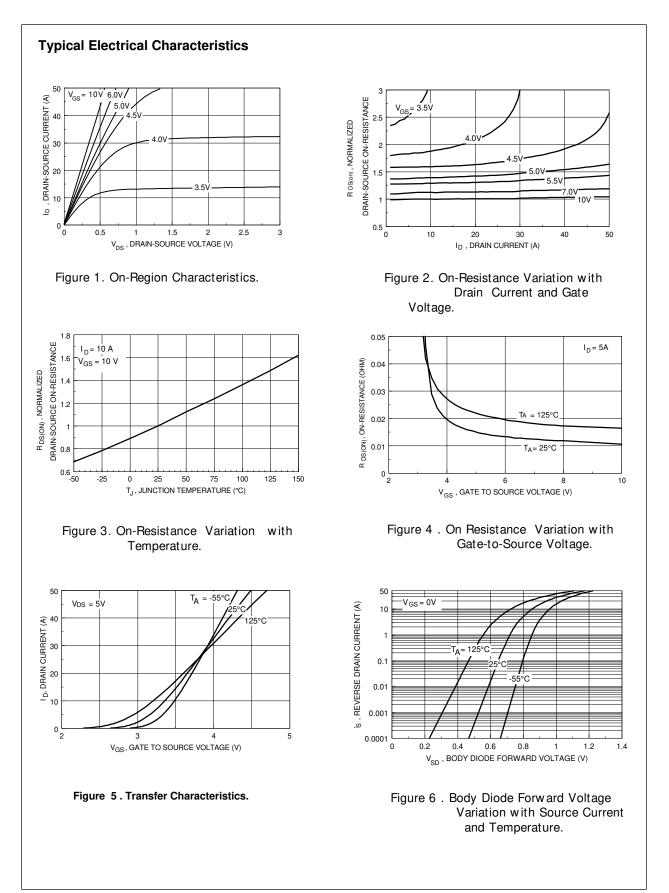


b. 105°C/W on a 0.02 in² pad of 2oz copper.

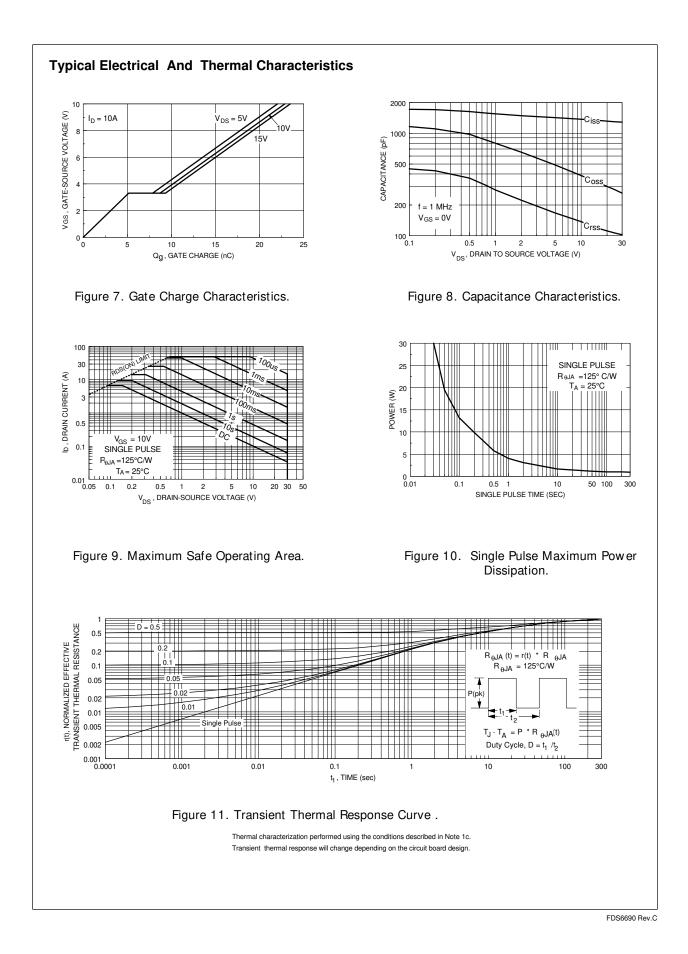


Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width \leq 300µs, Duty Cycle \leq 2.0%.



FDS6690 Rev.C



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